

ESE 570: Digital Integrated Circuits and VLSI Fundamentals

Lec 2: January 22, 2019
MOS Fabrication pt. 1: Physics and Methodology



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Lecture Outline

- Digital CMOS Basics
- VLSI Fundamentals
- Fabrication Process

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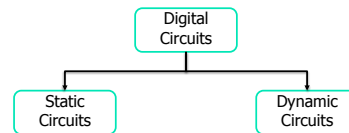
2

Digital CMOS Basics



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Classification of Digital CMOS Circuits

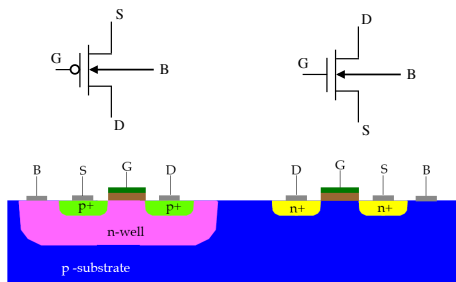


- Static Circuit
 - In steady-state the output is evaluated via a low-impedance path between the output and VDD or GND, respectively. I.e. the output is actively driven.
- Dynamic Circuit
 - In steady-state the output is evaluated due to the presence or absence of charge, respectively, stored on the output node capacitance.

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4

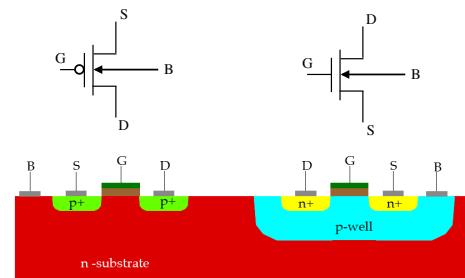
MOS Transistors



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5

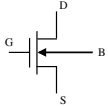
MOS Transistors



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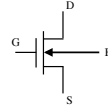
6

Ideal nMOS and pMOS Characteristics

SYMBOLS	SWITCH CHARACTERISTICS
N- SWITCH	  $g = 0$  $g = 1$

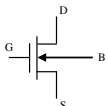
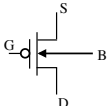
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Ideal nMOS and pMOS Characteristics

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1	Weak 1						

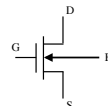
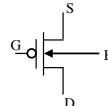
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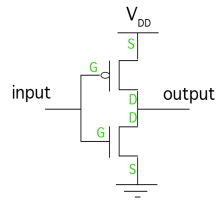
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Ideal nMOS and pMOS Characteristics

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0	Weak 0						
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Ideal CMOS Inverter



Inverter Truth Table

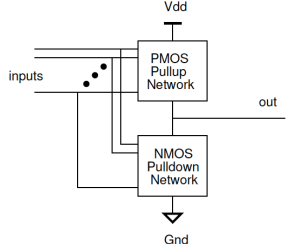
INPUT	OUTPUT
0	1
1	0

Inverter Symbol



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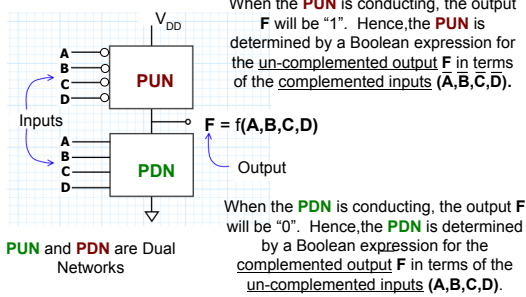
CMOS Gates



□ Complementary Metal Oxide Semiconductor

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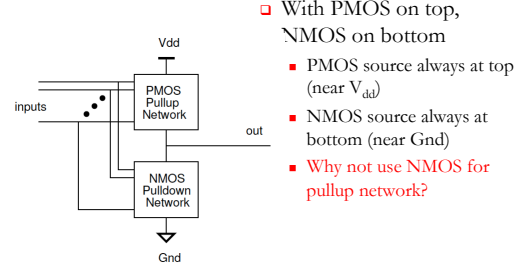
CMOS Gates



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13

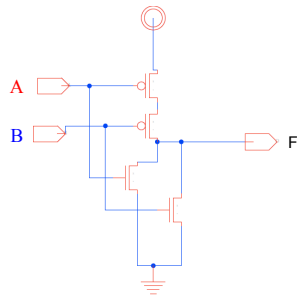
Static CMOS Source/Drains



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14

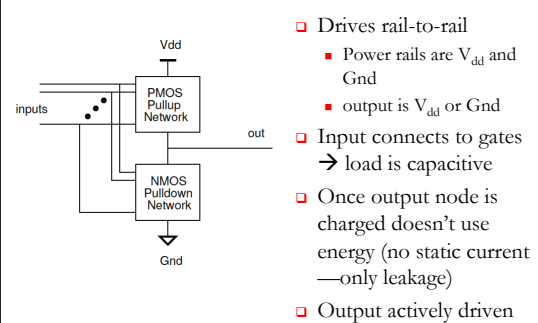
What gate is this?



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15

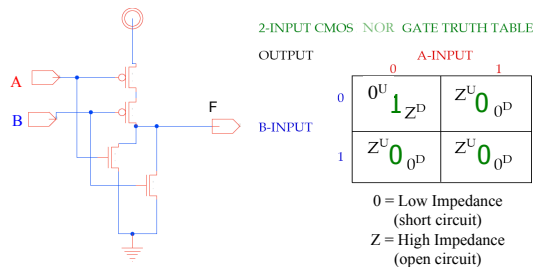
Static CMOS Gate Structure



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16

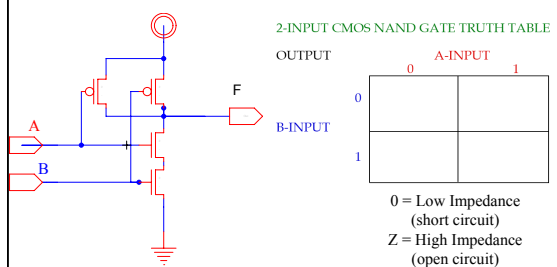
Two-Input CMOS NOR Gate



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17

Two-Input CMOS NAND Gate



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18

Two-Input CMOS NAND Gate

2-INPUT CMOS NAND GATE TRUTH TABLE

		A-INPUT	
		0	1
B-INPUT	0	1 ^U	1 ^U
	1	0 ^D	0 ^D

0 = Low Impedance (short circuit)
Z = High Impedance (open circuit)

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Gate Design Example

Design gate to perform: $f = (\bar{a} + \bar{b}) \cdot \bar{c}$

Strategy:

1. Use static CMOS structure
2. Design PMOS pullup for f
3. Use DeMorgan's Law to determine f'
4. Design NMOS pulldown for f'

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Gate Design Example

Design gate to perform: $f = (\bar{a} + \bar{b}) \cdot \bar{c}$

Convince yourself with a truth table.

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Constructing Compound CMOS Gates

$$F = (A \cdot B + C \cdot D)$$

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VLSI Fundamentals

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Oracle SPARC M7 Processor

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VLSI Hierarchical Representations

- Complex digital systems can be sub-divided in a hierarchical manner
- Highly automated techniques exist for converting high level descriptions of system behaviour to a detailed implementation prescription to fabricate a chip
- To do this, a set of **abstractions** and **domains** have been developed to describe integrated electronic systems

Design Domains

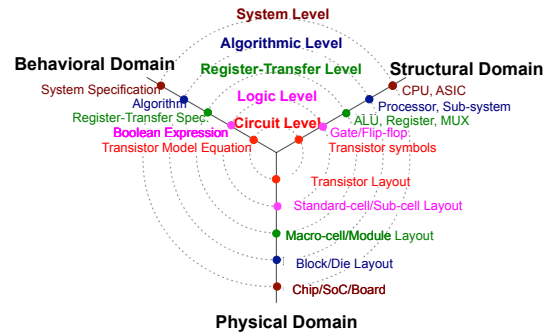
- Designs are represented in three **domains**
 - Behavioral** – What does the system do?
 - Structural** – How are the elements connected?
 - Physical** – How is the structure to be fabricated?

Design Abstractions

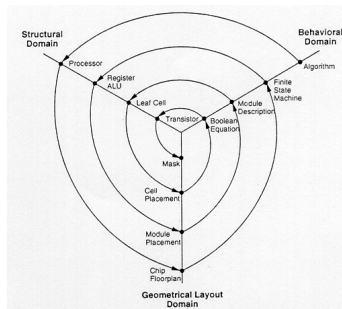
- Each domain can be specified at a variety of levels of **abstraction**
 - Architectural
 - Algorithmic
 - Module or Functional Block
 - Logical
 - Switch
 - Circuit

Higher Level
↓
Lower Level

Y-Chart: **Abstractions** in three **Domains**



Y-Chart: **Abstractions** in three **Domains**



Goal of All VLSI Design Enterprises

- Convert system specs into an IC design in **MINIMUM TIME** and with **MAXIMUM LIKLIHOOD** that the Design will **PEFORM AS SPECIFIED** when fabricated.
- MAX YIELD** + **MIN DEVELOPMENT TIME** + **MIN DIE AREA** => **MIN COST**

Fabrication Details



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Silicon Ingot and Wafer Manufacturing

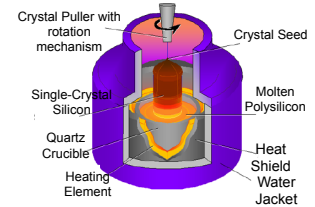
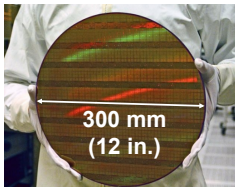


Image from Quirk & Serda

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32

Silicon Wafer Manufacturing



- The ROI of 450mm wafers is compelling:
 - A 450mm fab with equal wafer capacity to a 300mm fab can produce 2x the amount of die.
 - A 14nm die from a 450mm wafer will cost 23% less than the same die from a 300mm wafer.

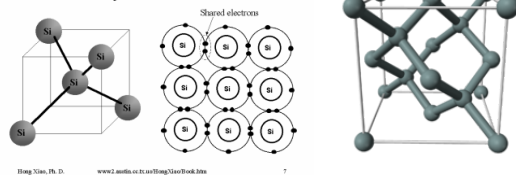
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33

Silicon Lattice

- Forms into crystal lattice

Crystal Structure of Single Crystal Silicon

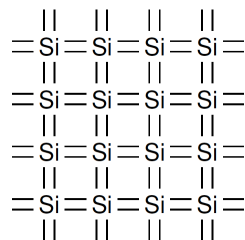


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34

Silicon Lattice

- Cartoon two-dimensional view

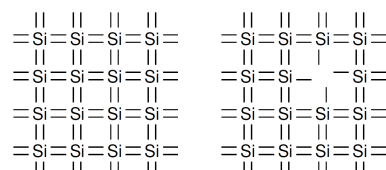


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Doping

- Add impurities to Silicon Lattice
 - Replace a Si atom at a lattice site with another



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Doping Elements

<http://chemistry.about.com/od/imagesclipartstructures/ig/Science-Pictures/Periodic-Table-of-the-Elements.htm>

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Doping with P (N-type)

- End up with extra electrons
 - Donor electrons
- Not tightly bound to atom
 - Low energy to displace
 - Easy for these electrons to move

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Doping with B (P-type)

- End up with electron vacancies -- Holes
 - Acceptor electron sites
- Easy for electrons to shift into these sites
 - Low energy to displace
 - Easy for the electrons to move
 - Movement of an electron best viewed as movement of hole

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IC Manufacturing Steps

Fabrication involves many repetitions of four basic steps

- Photolithography: transfer mask patterns to the chip
- Diffusion or Ion Implantation: selective doping of Si
- Oxidation: SiO_2 growth
- Deposition: Al, polysilicon and Si_3N_4 (silicon nitride) thin films

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Fabrication

- Start with Silicon wafer
- Dope
- Grow Oxide (SiO_2)
- Deposit Metal
- Mask/Etch to define where features go

<https://youtu.be/35jWSQXku74?t=121>

Time Code: 2:00-4:30

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Photolithography

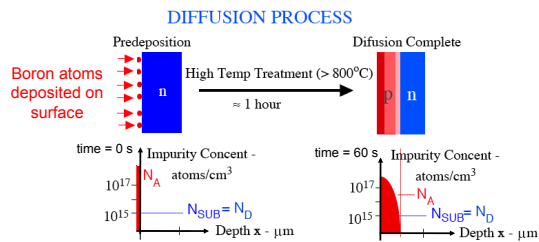
- Positive Photoresist -> exposed photoresist becomes soluble to certain chemicals.
- Negative Photoresist -> exposed photoresist becomes insoluble to certain chemicals.
- Positive Photoresist has higher resolution than Negative Photoresist

Methods of Inserting Impurity Atoms into Si Substrate

- Diffusion (impurity applied at Si surface, high temperature and long time, control of doping concentration not very precise)
- Ion implantation (impurity applied by scanning a high energy focussed ion beam at Si surface, low temperature, high acceleration, precise control of doping concentration)

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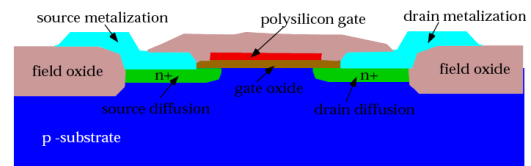
CMOS Processing Technology



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43

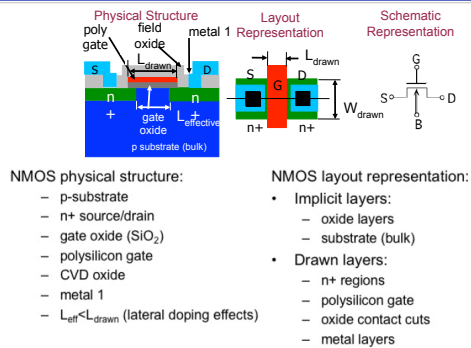
Fabricated n-MOS Transistor



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44

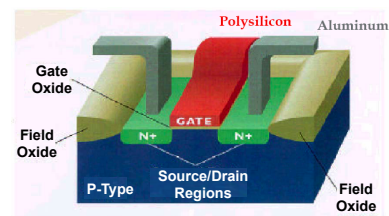
n-MOS Transistor Representations



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45

nMOS Transistor from a 3D Perspective

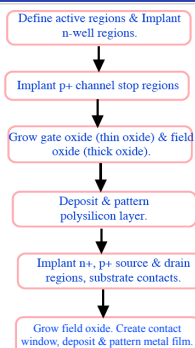


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46

Fabrication Process

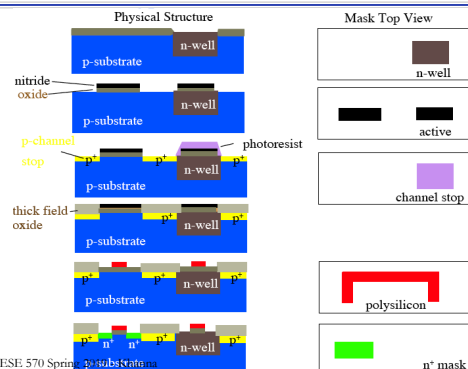
Simplified process sequence for the fabrication of an n-well CMOS IC (p substrate) with a single polysilicon layer and single metal layer



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47

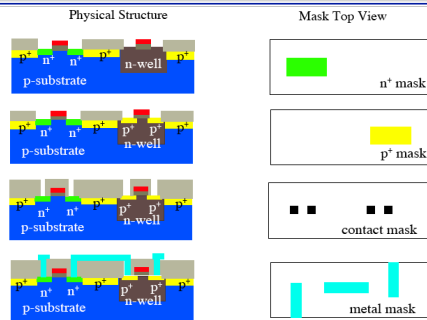
Typical N-Well CMOS Process



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48

Typical N-Well CMOS Process

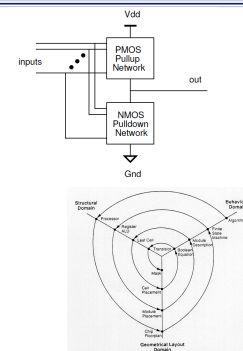


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49

Big Idea

- Systematic construction of any gate from transistors with CMOS PUN and PDN
- Hierarchical design process in three domains (behavioural, structural, and physical) allows for complicated designs motivated cost as a function of performance, yield and design time



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50

Admin

- New classroom: Towne 311
- Behind the scenes programming note:
 - Additional grader: Yifeng Zhang
- Enroll in Piazza site
 - piazza.com/upenn/spring2019/ese570
- Homework 1 due Friday
 - Journal articles may show up in lecture...

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51